

Corrigendum No 1

Date: 31/07/2019

This is with reference to the tender notification for **Atomic Force Microscope with accessories**, Tender Notification No: NITK/CRF/AFM/04 Dated: 09/07/2019. Prospective bidders may kindly note the following corrections in the technical specifications (**Annexure H**):

S.No.	Originally tendered Specifications	Amended Specifications
1.	<u>Item 2: Scanners</u> Sub-item d) Z (vertical) scanner max. range: 15 µm or more, with option to upgrade to 30 µm to be quoted as optional item	Z (vertical) scanner max. range: 15 µm or more, with option to upgrade to 25µm or more to be quoted as optional item
2.	<u>Item 4: Tip-Sample Viewing</u> Sub-item b) The resolution of the optical microscope must be less than or equal to 1 µm or better Sub-item c) CCD should have 5 or more mega pixel resolution	The resolution of the optical microscope must be less than or equal to 2µm or better Both CCD or CMOS technology are acceptable as long as the resolution is 5 MP or more.
3.	<u>Item 5: Sample Holder</u> Sub-item e) Stage/sample movement: XY-translation to image different areas of the sample must be motorized with at least 20 x 20 mm or higher X, Y movement and at least 20 mm or higher Z movement or more.	Stage/sample movement: XY-translation to image different areas of the sample must be motorized with at least 20 x 20mm or higher X, Y movement and at least 5 mm or higher Z movement or more with the option of accommodating samples of > 20 mm thickness
4.	<u>Item 6: Sample Size</u> Sub-item b) Max. sample weight 500 g or more	Max. sample weight upto 500 g
5.	<u>Item 7: Controller Electronics</u> Sub-item c) DACs with 24 bit or more resolution for X, Y, and Z scanner positioning Sub-item d) 24-bit ADCs and adaptive filters for high-resolution and low-noise data	DACs with at least 20 bit or more resolution for X, Y, and Z scanner positioning At least 20-bit ADCs and adaptive filters for high-resolution and low-noise data
6	<u>Optional Items to be quoted and pricing to be indicated separately for future upgrades:</u>	

	<p>a) External high voltage PFM kit upto 150 V or more</p> <p>b) Tilting Stage for side-wall thickness</p> <p>c) Vacuum Chuck Sample holder option</p>	<p>External high voltage PFM kit at least 100 V or more</p> <p>Absolutely essential. If it is not available with the vendor, the vendor can arrange from a third party. Tilt angles upto 20° desired (either stepped variation or continuous).</p> <p>Absolutely essential. If it is not available with the vendor, the vendor can arrange from a third party. Vacuum Chuck Sample Holder must be operable with voltage bias to sample in the range ± 10 V or higher.</p>
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The last date for bid submission, in view of the corrigendum is now extended. Bids must reach the address given in the bid document by **5.00PM on or before August 30, 2019 (Friday)**.

Sd/-
Chairman
Central Research Facility
NITK, Surathkal